SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

- Processed to MIL-PRF-38535 (QML)
- Operating Temperature Ranges:
 - Military (M) –55°C to 125°C
 - Special (S) -55°C to 105°C
- SMD Approval
- High-Performance Floating-Point Digital Signal Processor (DSP):
 - SMJ320C31-60 (5 V)
 33-ns Instruction Cycle Time
 330 Million Operations Per Second (MOPS), 60 Million Floating-Point Operations Per Second (MFLOPS),
 30 Million Instructions Per Second (MIPS)
 - SMJ320C31-50 (5 V)
 40-ns Instruction Cycle Time
 275 MOPS, 50 MFLOPS, 25 MIPS
 - SMJ320C31-40 (5 V)
 50-ns Instruction Cycle Time
 220 MOPS, 40 MFLOPS, 20 MIPS
 - SMJ320LC31-40 (3.3 V)
 50-ns Instruction Cycle Time
 220 MOPS, 40 MFLOPS, 20 MIPS
 - SMQ320LC31-40 (3.3 V)
 50-ns Instruction Cycle Time
 220 MOPS, 40 MFLOPS, 20 MIPS
- 32-Bit High-Performance CPU
- 16-/32-Bit Integer and 32-/40-Bit Floating-Point Operations
- 32-Bit Instruction and Data Words, 24-Bit Addresses
- Two 1K Word × 32-Bit Single-Cycle Dual-Access On-Chip RAM Blocks
- Boot-Program Loader
- 64-Word × 32-Bit Instruction Cache
- Eight Extended-Precision Registers
- Two Address Generators With Eight Auxiliary Registers and Two Auxiliary Register Arithmetic Units (ARAUs)

- Two Low-Power Modes
- On-Chip Memory-Mapped Peripherals:
 - One Serial Port Supporting 8-/16-/24-/32-Bit Transfers
 - Two 32-Bit Timers
 - One-Channel Direct Memory Access (DMA) Coprocessor for Concurrent I/O and CPU Operation
- Fabricated Using Enhanced Performance Implanted CMOS (EPIC™) Technology by Texas Instruments (TI)
- Two- and Three-Operand Instructions
- 40/32-Bit Floating-Point/Integer Multiplier and Arithmetic Logic Unit (ALU)
- Parallel ALU and Multiplier Execution in a Single Cycle
- Block-Repeat Capability
- Zero-Overhead Loops With Single-Cycle Branches
- Conditional Calls and Returns
- Interlocked Instructions for Multiprocessing Support
- Bus-Control Registers Configure Strobe-Control Wait-State Generation
- Validated Ada Compiler
- Integer, Floating-Point, and Logical Operations
- 32-Bit Barrel Shifter
- One 32-Bit Data Bus (24-Bit Address)
- Packaging
 - 132-Lead Ceramic Quad Flatpack With Nonconductive Tie-Bar (HFG Suffix)
 - 141-Pin Ceramic Staggered Pin Grid- Array Package (GFA Suffix)
 - 132-Lead TAB Frame
 - 132-Lead Plastic Quad Flatpack (PQ Suffix)

description

The SMJ320C31, SMJ320LC31, and SMQ320LC31 digital signal processors (DSPs) are 32-bit, floating-point processors manufactured in $0.6-\mu m$ triple-level-metal CMOS technology. The devices are part of the SMJ320C3x generation of DSPs from Texas Instruments.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

EPIC is a trademark of Texas Instruments Incorporated



Not Recommended for New Designs

SMJ320C31, SMJ320LC31, SMQ320LC31 DIGITAL SIGNAL PROCESSORS

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

description (continued)

The SMJ320C3x internal busing and special digital-signal-processing instruction set have the speed and flexibility to execute up to 60 MFLOPS. The SMJ320C3x optimizes speed by implementing functions in hardware that other processors implement through software or microcode. This hardware-intensive approach provides performance previously unavailable on a single chip.

The SMJ320C3x can perform parallel multiply and ALU operations on integer or floating-point data in a single cycle. Each processor also possesses a general-purpose register file, a program cache, dedicated ARAUs, internal dual-access memories, one DMA channel supporting concurrent I/O, and a short machine-cycle time. High performance and ease of use are results of these features.

General-purpose applications are greatly enhanced by the large address space, multiprocessor interface, internally and externally generated wait states, one external interface port, two timers, one serial port, and multiple-interrupt structure. The SMJ320C3x supports a wide variety of system applications from host processor to dedicated coprocessor.

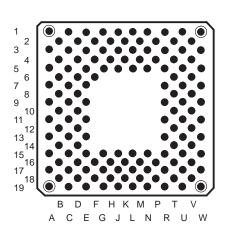
High-level-language support is easily implemented through a register-based architecture, large address space, powerful addressing modes, flexible instruction set, and well-supported floating-point arithmetic.

For additional information when designing for cold temperature operation, please see Texas Instruments application report 320C3x, 320C4x and 320MCM42x Power-up Sensitivity at Cold Temperature, literature number SGUA001.

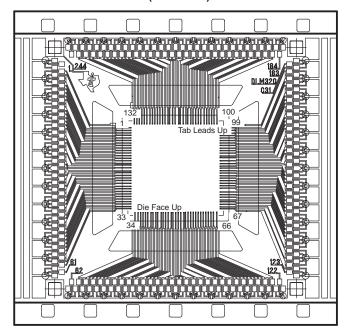


SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

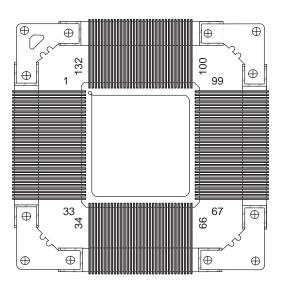
141-PIN GFA STAGGERED GRID ARRAY PACKAGE (BOTTOM VIEW)



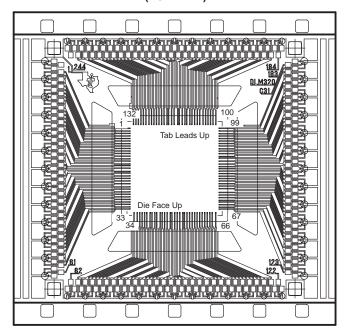
TA PACKAGE (TOP VIEW)



132-PIN HFG QUAD FLATPACK (TOP VIEW)



TB PACKAGE (TOP VIEW)

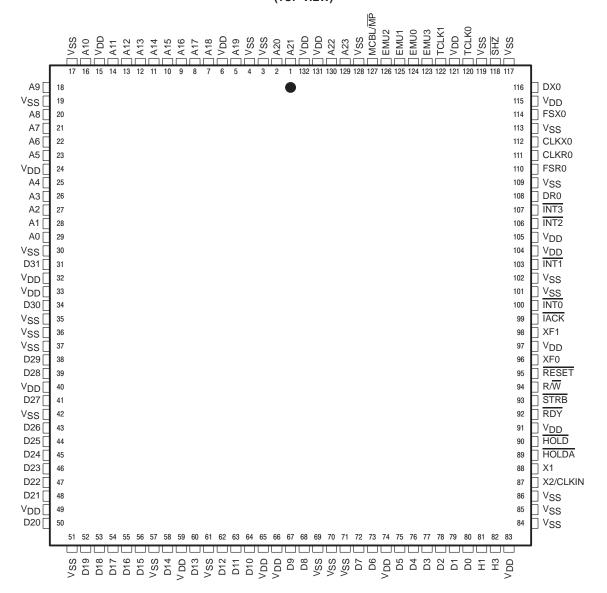


SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

SMQ320LC31 pinout (top view)

The SMQ320LC31 device is also packaged in a132-pin plastic quad flatpack (PQ Suffix). The full part numbers are SMQ320LC31PQM40 and 5962-9760601NXB.

PQ PACKAGE (TOP VIEW)





SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

Terminal Assignments

	PI	N			P	N	
	NUMBER				NUMBER		
PQ PKG	HFG PKG	GFA PKG	NAME	PQ PKG	HFG PKG	GFA PKG	NAME
29	12	L1	A0	64	47	W9	D10
28	11	K2	A1	63	46	U9	D11
27	10	J1	A2	62	45	V8	D12
26	9	J3	А3	60	43	W7	D13
25	8	G1	A4	58	41	U7	D14
23	6	F2	A5	56	39	V6	D15
22	5	E1	A6	55	38	W5	D16
21	4	E3	A7	54	37	U5	D17
20	3	D2	A8	53	36	V4	D18
18	1	C1	A9	52	35	W3	D19
16	131	C3	A10	50	33	U3	D20
14	129	B2	A11	48	31	V2	D21
13	128	A1	A12	47	30	W1	D22
12	127	C5	A13	46	29	R3	D23
11	126	B4	A14	45	28	T2	D24
10	125	А3	A15	44	27	U1	D25
9	124	C7	A16	43	26	N3	D26
8	123	B6	A17	41	24	P2	D27
7	122	C9	A18	39	22	R1	D28
5	120	B8	A19	38	21	L3	D29
2	117	A7	A20	34	17	M2	D30
1	116	A9	A21	31	14	N1	D31
130	113	B10	A22	108	91	C19	DR0
129	112	A11	A23	116	99	C17	DX0
111	94	E17	CLKR0	124	107	B14	EMU0
112	95	A19	CLKX0	125	108	A13	EMU1
80	63	W19	D0	126	109	B12	EMU2
79	62	V16	D1	123	106	A15	EMU3
78	61	W17	D2	110	93	D18	FSR0
77	60	U13	D3	114	97	B18	FSX0
76	59	V14	D4	81	73	P18	HOLD
75	58	W15	D5	82	72	R19	HOLDA
73	56	U11	D6	90	64	V18	H1
72	55	V12	D7	89	65	U17	НЗ
68	51	W11	D8	99	82	H18	IACK
67	50	V10	D9	100	83	J17	INT0



[†] CVSS, VSSL, and IVSS are on the same plane. ‡ AVDD, DVDD, CVDD, and PVDD are on the same plane. § VSUBS connects to die metallization. Tie this pin to clean ground.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

Terminal Assignments (Continued)

	Р	IN	minai Assignin	PIN						
	NUMBER				NUMBER					
PQ PKG	HFG PKG	GFA PKG	NAME	PQ PKG	HFG PKG	GFA PKG	NAME			
103	86	E19	INT1	30	18	P4	∨ _{SSL} †			
106	89	F18	ĪNT2	35	19	T10	∨ _{SSL} †			
107	90	G17	ĪNT3	36	20	K4	DV _{SS}			
127	110	C11	MCBL/MP	37	25	T4	IV _{SS} †			
92	77	L19	R/W	42	34	G3	DVSS			
95	75	N17	RDY	51	40	K16	CV _{SS} †			
94	78	K18	RESET	57	44	T8	IV _{SS} †			
118	101	A17	SHZ	61	52	T12	DV _{SS}			
93	76	M18	STRB	69	53	R11	V _{SSL} †			
120	103	B16	TCLK0	70	54	J15	V _{SSL} †			
	105	C15	TCLK1	71	67	W13	DVSS			
	121	G5	AV _{DD} ‡	84	68	D10	CV _{SS} †			
6	130	E7	AV _{DD} ‡	85	69	D16	IV _{SS} †			
15	7	E5	AV _{DD} ‡	86	84	T16	DVSS			
24	15	N5	V_{DDL}	101	85	D12	V _{SSL} †			
32	16	R5	V_{DDL}	102	92	F16	CV _{SS} †			
33	23	H4	DV _{DD} ‡	109	96	H16	IV _{SS} †			
40	32	J5	DV _{DD} ‡	113	100	D14	V _{SUBS} §			
49	42	T14	DV _{DD} ‡	117	102	U15	DVSS			
59	48	R7	V_{DDL}	119	111	C13	CV _{SS} †			
65	49	R9	V_{DDL}	128	71	T18	X1			
66	57	R13	DV _{DD} ‡	88	70	U19	X2/CLKIN			
74	66	R15	DV _{DD} ‡	87	79	J19	XF0			
83	74	P16	CV _{DD} ‡	96	81	G19	XF1			
91	80	N15	CV _{DD} ‡	98		F6	No Connect			
97	87	G15	V_{DDL}			D4	DVSS			
104	88	E15	V _{DDL}			N19	DVSS			
105	98	L15	PV _{DD} ‡			R17	DVSS			
115	104	E9	PV _{DD} ‡			L17	DV _{SS}			
121	114	E13	V_{DDL}			M16	DVSS			
131	115	E11	V_{DDL}			D6	DVSS			
132	118	L5	V _{SSL} †			A5	DVSS			
3	119	H2	DVSS			D8	DVSS			
4	132	M4	CV _{SS} †							
17	2	F4	DV _{SS}							
19	13	Т6	CV _{SS} †							



[†] CV_{SS}, V_{SSL}, and IV_{SS} are on the same plane. ‡ AV_{DD}, DV_{DD}, CV_{DD}, and PV_{DD} are on the same plane. § V_{SUBS} connects to die metallization. Tie this pin to clean ground.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

Terminal Functions

TERMINAL NAME QTY		TYPE†	DESCRIPTION		NDITIO WHEN		
		•	PRIMARY-BUS INTERFACE				
D31-D0	32	I/O/Z	32-bit data port	S	Н	R	
A23-A0	24	O/Z	24-bit address port	S	Н	R	
R/\overline{W}	1	O/Z	Read/write. R/\overline{W} is high when a read is performed and low when a write is performed over the parallel interface.	S	Н	R	
STRB	1	O/Z	External-access strobe	S	Н		
RDY	1	I	Ready. $\overline{\text{RDY}}$ indicates that the external device is prepared for a transaction completion.				
HOLD	1	I	Hold. When HOLD is a logic low, any ongoing transaction is completed. A23 – A0, D31 – D0, STRB, and R/W are placed in the high-impedance state and all transactions over the primary-bus interface are held until HOLD becomes a logic high or until the NOHOLD bit of the primary-bus-control register is set.				
HOLDA	1	O/Z	Hold acknowledge. HOLDA is generated in response to a logic low on HOLD. HOLDA indicates that A23 A0 D31 D0 STRB and R/W are in the high-impedance state.				
		-	CONTROL SIGNALS				
RESET	1	I	Reset. When RESET is a logic low, the device is in the reset condition. When RESET becomes a logic high, execution begins from the location specified by the reset vector.				
INT3-INT0	4	- 1	External interrupts				
ĪACK	1	O/Z	Interrupt acknowledge. IACK is generated by the IACK instruction. IACK can be used to indicate the beginning or the end of an interrupt-service routine.	S			
MCBL/MP	1	1	Microcomputer boot-loader/microprocessor mode-select				
SHZ	1	I	Shutdown high impedance. When active, SHZ shuts down the device and places all pins in the high-impedance state. SHZ is used for board-level testing to ensure that no dual-drive conditions occur. CAUTION: A low on SHZ corrupts the device memory and register contents. Reset the device with SHZ high to restore it to a known operating condition.				
XF1, XF0	2	I/O/Z	External flags. XF1 and XF0 are used as general-purpose I/Os or to support interlocked processor instruction.	S		R	
			SERIAL PORT 0 SIGNALS				
CLKR0	1	I/O/Z	Serial port 0 receive clock. CLKR0 is the serial shift clock for the serial port 0 receiver.	S		R	
CLKX0	1	I/O/Z	Serial port 0 transmit clock. CLKX0 is the serial shift clock for the serial port 0 transmitter.	Ø		R	
DR0	1	I/O/Z	Data-receive. Serial port 0 receives serial data on DR0.	S		R	
DX0	1	I/O/Z	Data-transmit output. Serial port 0 transmits serial data on DX0.	S		R	
FSR0	1	I/O/Z	Frame-synchronization pulse for receive. The FSR0 pulse initiates the data-receive process using DR0.	S		R	
FSX0	1	I/O/Z	Frame-synchronization pulse for transmit. The FSX0 pulse initiates the data-transmit process using DX0.	S		R	
			TIMER SIGNALS				
TCLK0	1	I/O/Z	Timer clock 0. As an input, TCLK0 is used by timer 0 to count external pulses. As an output, TCLK0 outputs pulses generated by timer 0.	S			
TCLK1	1	I/O/Z	Timer clock 1. As an input, TCLK0 is used by timer 1 to count external pulses. As an output, TCLK1 outputs pulses generated by timer 1.	S			

[†] I = input, O = output, Z = high-impedance state ‡ S = SHZ active, H = HOLD active, R = RESET active



Not Recommended for New Designs

SMJ320C31, SMJ320LC31, SMQ320LC31 DIGITAL SIGNAL PROCESSORS

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

Terminal Functions (Continued)

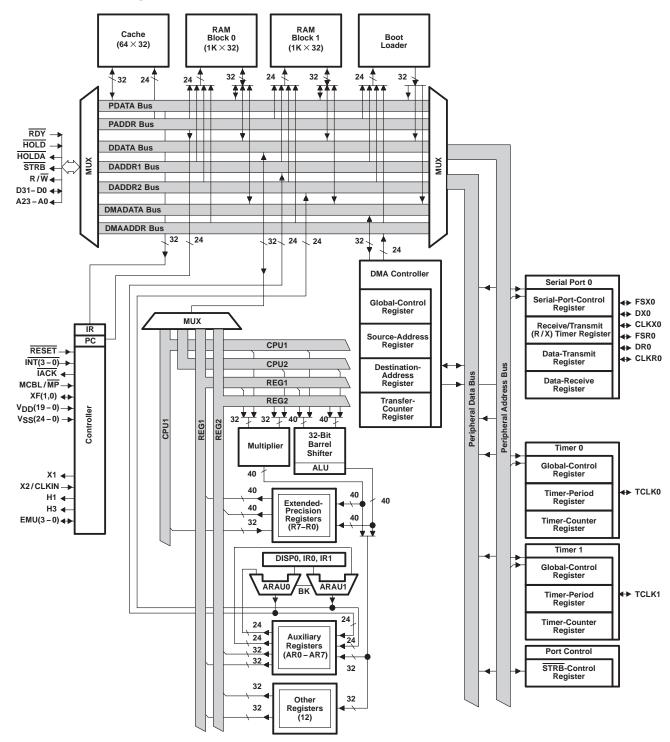
TERMINA NAME	TERMINAL NAME QTY		DESCRIPTION	CONDITIONS WHEN SIGNAL IS Z TYPE‡					
SUPPLY AND OSCILLATOR SIGNALS									
H1	1	O/Z	External H1 clock. H1 has a period equal to twice CLKIN.	S					
H3	1	O/Z	External H3 clock. H3 has a period equal to twice CLKIN.	S					
V _{DD}	20	ı	5-V supply for 'C31 devices and 3.3-V supply for 'LC31 devices. All must be connected to a common supply plane.§						
VSS	25	- 1	Ground. All grounds must be connected to a common ground plane.						
X1	1	0	Output from the internal-crystal oscillator. If a crystal is not used, X1 should be left unconnected.						
X2/CLKIN	1	I	Internal-oscillator input from a crystal or a clock						
	RESERVED¶								
EMU2-EMU0	3	I	Reserved for emulation. Use pullup resistors to V _{DD}						
EMU3			S						

[†] I = input, O = output, Z = high-impedance state ‡ S = SHZ active, H = HOLD active, R = RESET active

[§] Recommended decoupling capacitor value is 0.1 μF .

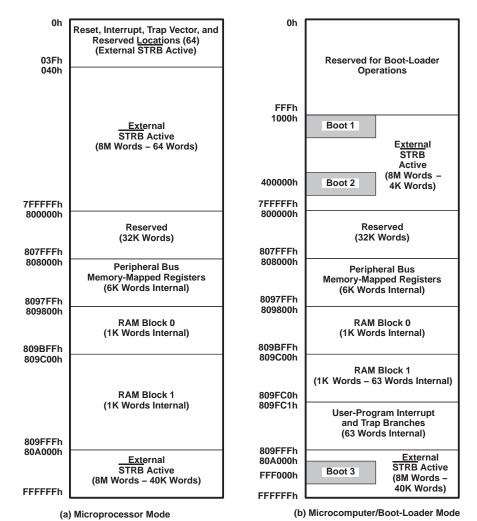
 $[\]P$ Follow the connections specified for the reserved pins. Use 18-k Ω – 22-k Ω pullup resistors for best results. All V_{DD} supply pins must be connected to a common supply plane, and all ground pins must be connected to a common ground plane.

functional block diagram



SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

memory map†



[†] Figure 1 depicts the memory map for the SMJ320C31. See the *TMS320C3x Users Guide* (literature number SPRU031) for a detailed description of this memory mapping.

Figure 1. SMJ320C31 Memory Map

memory map (continued)

00h	Reset	809FC1h	INT0							
01h	INT0	809FC2h	INT1							
02h	INT1	809FC3h	INT2							
03h	INT2	809FC4h	INT3							
04h	INT3	9005056								
05h	XINT0	809FC5h	XINT0							
06h	RINT0	809FC6h	RINT0							
07h 08h	Reserved	809FC7h 809FC8h	Reserved							
09h	TINT0	809FC9h	TINT0							
0Ah	TINT1	809FCAh	TINT1							
0Bh	DINT	809FCBh	DINT							
0Ch 1Fh	Reserved	809FCCh 809FDFh	Reserved							
20h	TRAP 0	809FE0h	TRAP 0							
	•		•							
3Bh	TRAP 27	809FFBh	TRAP 27							
3Ch 3Fh	Reserved	809FFCh 809FFFh	Reserved							
	(a) Microprocessor Mode (b) Microcomputer/Boot-Loader Mode									

Figure 2. Reset, Interrupt, and Trap Vector/Branches Memory-Map Locations

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

memory map (continued)

808000h	DMA Global Control
808004h	DMA Source Address
808006h	DMA Destination Address
808008h	DMA Transfer Counter
808020h	Timer 0 Global Control
808024h	Timer 0 Counter
808028h	Timer 0 Period Register
808030h	Timer 1 Global Control
808034h	Timer 1 Counter
808038h	Timer 1 Period Register
808040h	Serial Global Control
808042h	FSX/DX/CLKX Serial Port Control
808043h	FSR/DR/CLKR Serial Port Control
808044h	Serial R/X Timer Control
808045h	Serial R/X Timer Counter
808046h	Serial R/X Timer Period Register
808048h	Data-Transmit
80804Ch	Data-Receive
808064h	Primary-Bus Control

†Shading denotes reserved address locations

Figure 3. Peripheral Bus Memory-Mapped Registers[†]

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

absolute maximum ratings over specified temperature range (unless otherwise noted)†

	'C31	'LC31
Supply voltage, V _{DD} (see Note 1)	0.3 V to 7 V	–0.3 V to 5 V
Input voltage, V _I	0.3 V to 7 V	–0.3 V to 5 V
Output voltage, V _O	0.3 V to 7 V	–0.3 V to 5 V
Continuous power dissipation (worst case) (see Note 2) (for S	1.7 W MJ320C31-33)	850 mW (for SMJ320LC31-33)
Operating case temperature, T _C	-55°C to 125°C	– –55°C to 125°C
Storage temperature, T _{stq} –	65°C to 150°C	– 65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to VSS.

2. Actual operating power is less. This value was obtained under specially produced worst-case test conditions for the TMS320C31-33 and the TMS320LC31-33, which are not sustained during normal device operation. These conditions consist of continuous parallel writes of a checkerboard pattern to both primary and extension buses at the maximum rate possible. See normal (I_{CC}) current specification in the electrical characteristics table and also read *Calculation of TMS320C30 Power Dissipation Application Report* (literature number SPRA020).

recommended operating conditions (see Note 3)

						'LC31			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V_{DD}	Supply voltage (DV _{DD} , etc.)		4.75	5	5.25	3.13	3.3	3.47	V
VSS	Supply voltage (CV _{SS} , etc.)		0			0		V	
.,	High-level input voltage (except RESET)		2.1		V _{DD} + 0.3*	1.8		V _{DD} + 0.3*	V
VIH	High-level input voltage (RESET)		2.2		V _{DD} + 0.3*	2.2		V _{DD} + 0.3*	V
V _{IL}	Low-level input voltage		- 0.3*		0.8	- 0.3*		0.6	V
lOH	High-level output current				- 300			- 300	μΑ
lOL	Low-level output current				2			2	mA
TC	Operating case temperature	'320C31-40 '320C31-50 '320C31-60 '320LC31-40	–55 –55 –55		125 125 105	-55		125	°C
VTH	High-level input voltage for CLKIN	ı	3.0		V _{DD} + 0.3*	2.5		V _{DD} + 0.3*	V

^{*} This parameter is not production tested.

NOTE 3: All voltage values are with respect to VSS. All input and output voltage levels are TTL-compatible. CLKIN can be driven by a CMOS clock.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

electrical characteristics over recommended ranges of supply voltage (unless otherwise noted) (see Note 3)[†]

	DADAMETED		T-(T CONDITION	10		'C31			'LC31		
	PARAMETER		TEST CONDITIONS			MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNIT
VOH	High-level output	t voltage	$V_{DD} = MIN, I$	$I_{DD} = MIN, I_{OH} = MAX$			3		2			V
VOL	Low-level output	voltage	$V_{DD} = MIN, I$	OH = MAX			0.3	0.6			0.4	V
IZ	High-impedance	current	$V_{DD} = MAX$	DD = MAX				+ 20	- 20		+ 20	μΑ
II	Input current		V _I = V _{SS} to V	= V _{SS} to V _{DD}				+ 10	- 10		+ 10	μΑ
I _{IP}	Input current (wit pullup)	h internal	Inputs with inte	puts with internal pullups§				20	- 600		10	μΑ
			T _A = 25°C,	f _X = 40 MHz	'C31-40 'LC31-40		160	400		150	300	
ICC	Supply current ¶#	•	$V_{DD} = MAX$	f _X = 50 MHz	'C31-50		200	425				mA
				f _X = 60 MHz	'C31-60		225	475				
I_{DD}	Supply current		Standby, I	DLE2 Clock	ks shut off		50			20		μΑ
	Input capacitance	All inputs 6	except CLKIN					15*			15*	
Ci		CLKIN						25			25	pF
Co	Output capacitar	nce						20*			20*	pF

[†] All input and output voltage levels are TTL compatible.

NOTE 3: All voltage values are with respect to VSS. All input and output voltage levels are TTL-compatible. CLKIN can be driven by a CMOS clock.

[‡] For 'C31, all typical values are at $V_{DD} = 5 \text{ V}$, $V_{A} = 25 \text{ °C}$. For 'LC31, all typical values are at $V_{DD} = 3.3 \text{ V}$, $V_{A} = 25 \text{ °C}$.

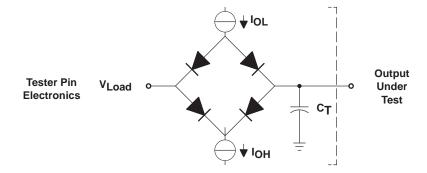
[§] Pins with internal pullup devices: INT3-INT0, MCBL/MP.

Actual operating current is less than this maximum value. This value was obtained under specially produced worst-case test conditions, which are not sustained during normal device operation. These conditions consist of continuous parallel writes of a checkerboard pattern to both primary and expansion buses at the maximum rate possible. See *Calculation of TMS320C30 Power Dissipation Application Report* (literature number SPRA020).

 $^{^{\#}}$ f_x is the input clock frequency.

^{*} This parameter is not production tested.

PARAMETER MEASUREMENT INFORMATION



Where: IOL = 2 mA (all outputs) IOH = $300 \,\mu\text{A}$ (all outputs) VLOAD = Selected to emulate $50\text{-}\Omega$ termination (typical value = 1.54 V). CT = 80-pF typical load-circuit capacitance

Figure 4. SMJ320C31 Test Load Circuit

signal transition levels for 'C31 (see Figure 5 and Figure 6)

TTL-level outputs are driven to a minimum logic-high level of 2.4 V and to a maximum logic-low level of 0.6 V. Output transition times are specified as follows:

- For a high-to-low transition on a TTL-compatible output signal, the level at which the output is said to be no longer high is 2 V and the level at which the output is said to be low is 1 V.
- For a low-to-high transition, the level at which the output is said to be no longer low is 1 V and the level at which the output is said to be high is 2 V.



Figure 5. TTL-Level Outputs

Transition times for TTL-compatible inputs are specified as follows:

- For a high-to-low transition on an input signal, the level at which the input is said to be no longer high is 2.1 V and the level at which the input is said to be low is 0.8 V.
- For a low-to-high transition on an input signal, the level at which the input is said to be no longer low is 0.8 V and the level at which the input is said to be high is 2.1 V.

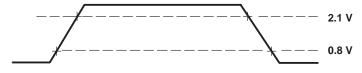
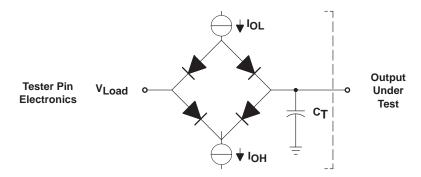


Figure 6. TTL-Level Inputs

PARAMETER MEASUREMENT INFORMATION



Where: IOL = 2 mA (all outputs) IOH = 300 μ A (all outputs) VLOAD = 2.15 V CT = 80-pF typical load-circuit capacitance

Figure 7. SMJ320LC31 Test Load Circuit

signal transition levels for 'LC31 (see Figure 8 and Figure 9)

Outputs are driven to a minimum logic-high level of 2 V and to a maximum logic-low level of 0.4 V. Output transition times are specified as follows:

- For a high-to-low transition on an output signal, the level at which the output is said to be no longer high is 2 V and the level at which the output is said to be low is 1 V.
- For a low-to-high transition, the level at which the output is said to be no longer low is 1 V and the level at which the output is said to be high is 2 V.



Figure 8. 'LC31 Output Levels

Transition times for inputs are specified as follows:

- For a high-to-low transition on an input signal, the level at which the input is said to be no longer high is 1.8 V and the level at which the input is said to be low is 0.6 V.
- For a low-to-high transition on an input signal, the level at which the input is said to be no longer low is 0.6 V and the level at which the input is said to be high is 1.8 V.

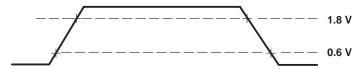


Figure 9. 'LC31 Input Levels



SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

PARAMETER MEASUREMENT INFORMATION

timing parameter symbology

Timing parameter symbols used herein were created in accordance with JEDEC Standard 100-A. In order to shorten the symbols, some of the pin names and other related terminology have been abbreviated as follows, unless otherwise noted:

Α	A23-A0	Н	H1 and H3
ASYNCH	Asynchronous reset signals	HOLD	HOLD
С	CLKX0	HOLDA	HOLDA
CI	CLKIN	IACK	IACK
CLKR	CLKR0	INT	INT3-INT0
CONTROL	Control signals	RDY	RDY
D	D31 – D0	RW	R/\overline{W}
DR	DR	RESET	RESET
DX	DX	S	STRB
FS	FSX/R	SCK	CLKX/R
FSX	FSX0	SHZ	SHZ
FSR	FSR0	TCLK	TCLK0, TCLK1, or TCLKx
GPI	General-purpose input	XF	XF0, XF1, or XFx
GPIO	General-purpose input/output; peripheral pin	XFIO	XFx switching from input to output
GPO	General-purpose output		

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

timing

Timing specifications apply to the SMJ320C31 and SMJ320LC31.

X2/CLKIN, H1, and H3 timing

The following table defines the timing parameters for the X2/CLKIN, H1, and H3 interface signals.

timing parameters for X2/CLKIN, H1, H3 (see Figure 10, Figure 11, Figure 12, and Figure 13)

NO.			'C31-40 'LC31-40		'C31	-50	'C31-60		UNIT
				MAX	MIN	MAX	MIN	MAX	
1	t _f (CI)	Fall time, CLKIN		5*		5*		4*	ns
2	tw(CIL)	Pulse duration, CLKIN low $t_{C(CI)} = min$	9		7		6		ns
3	tw(CIH)	Pulse duration, CLKIN high $t_{C(CI)} = min$	9		7		6		ns
4	tr(CI)	Rise time, CLKIN		5*		5*		4*	ns
5	t _C (CI)	Cycle time, CLKIN	25	303	20	303	16.67	303	ns
6	t _{f(H)}	Fall time, H1 and H3		3		3		3	ns
7	tw(HL)	Pulse duration, H1 and H3 low	P-5†		P-5†		P-4†		ns
8	tw(HH)	Pulse duration, H1 and H3 high	P-6†		P-6†		P-5†		ns
9	t _{r(H)}	Rise time, H1 and H3		3		3		3	ns
10	td(HL-HH)	Delay time. from H1 low to H3 high or from H3 low to H1 high	0	4	0	4	0	4	ns
11	t _C (H)	Cycle time, H1 and H3	50	606	40	606	33.3	606	ns

 $[\]dagger P = t_{C(CI)}$

^{*} This parameter is not production tested.

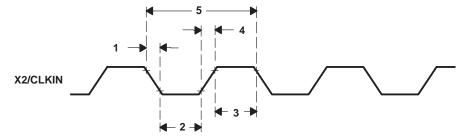


Figure 10. Timing for X2/CLKIN

X2/CLKIN, H1, and H3 timing (continued)

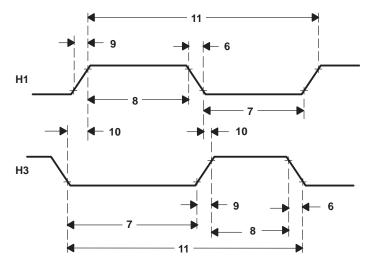


Figure 11. Timing for H1 and H3

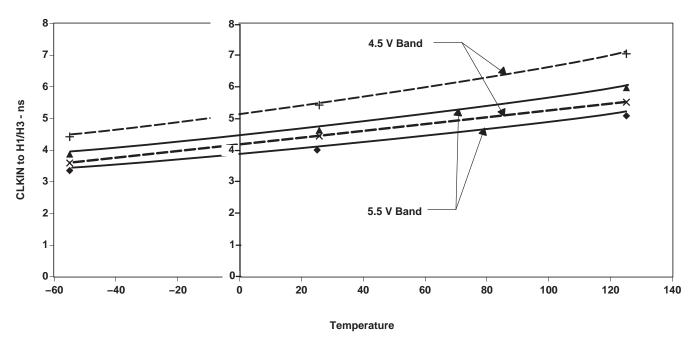


Figure 12. SMJ320C31 CLKIN to H1/H3 as a Function of Temperature (Typical)

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

X2/CLKIN, H1, and H3 timing (continued)

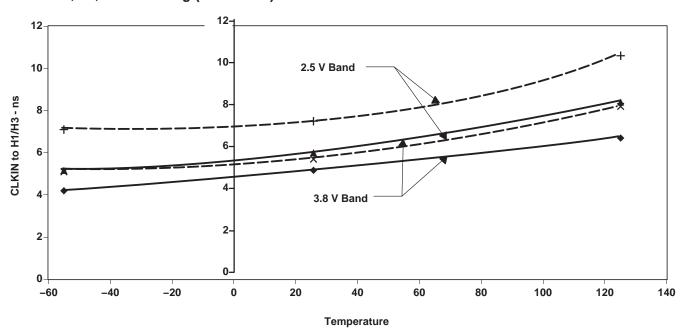


Figure 13. SMJ320LC31 CLKIN to H1/H3 as a Function of Temperature (Typical)



memory read/write timing

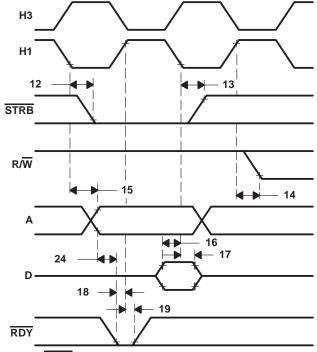
The following table defines memory read/write timing parameters for STRB.

timing parameters for memory (STRB = 0) read/write (see Figure 14 and Figure 15)†

NO.				'C31-40 'LC31-40		-50	'C31-60		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
12	td(H1L-SL)	Delay time, H1 low to STRB low	0*	6	0*	5	0*	5	ns
13	td(H1L-SH)	Delay time, H1 low to STRB high	0*	6	0*	5	0*	5	ns
14	td(H1H-RWL)R	Delay time, H1 high to R/\overline{W} low (read)	0*	9	0*	7	0*	6	ns
15	^t d(H1L-A)	Delay time, H1 low to A valid	0*	10	0*	10	0*	8	ns
16	t _{su(D-H1L)R}	Setup time, D before H1 low (read)	14		10		9		ns
17	th(H1L-D)R	Hold time, D after H1 low (read)	0		0		0		ns
18	t _{su} (RDY-H1H)	Setup time, RDY before H1 high	8		6		5		ns
19	th(H1H-RDY)	Hold time, RDY after H1 high	0		0		0		ns
20	td(H1H-RWH)W	Delay time, H1 high to R/\overline{W} high (write)		9		7		6	ns
21	t _V (H1L-D)W	Valid time, D after H1 low (write)		17		14		12	ns
22	th(H1H-D)W	Hold time, D after H1 high (write)	0		0		0		ns
23	^t d(H1H-A)W	Delay time, H1 high to A valid on back-to-back write cycles (write)		15		14		10	ns
24	td(A-RDY)	Delay time, RDY from A valid		7*		6*		6*	ns

[†] See Figure 16 for address bus timing variation with load capacitance greater than typical load-circuit capacitance (C_T = 80 pF).

^{*} This parameter is not production tested.



NOTE A: STRB remains low during back-to-back read operations.

Figure 14. Timing for Memory (STRB = 0) Read

memory read/write timing (continued)

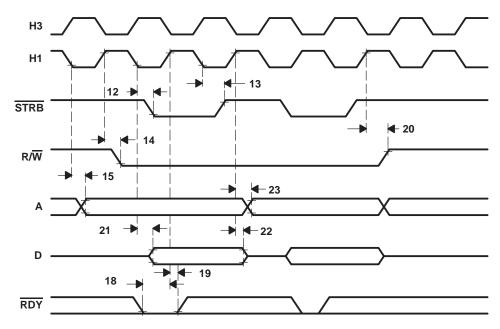
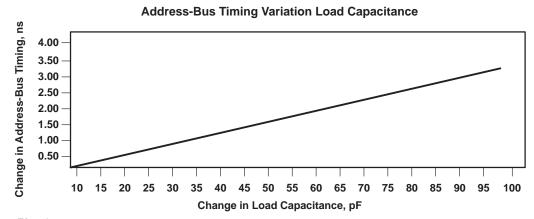


Figure 15. Timing for Memory ($\overline{STRB} = 0$) Write



NOTE A: 30 pF/ns slope

Figure 16. Address-Bus Timing Variation With Load Capacitance (see Note A)

XF0 and XF1 timing when executing LDFI or LDII

The following table defines the timing parameters for XF0 and XF1 during execution of LDFI or LDII.

timing for XF0 and XF1 when executing LDFI or LDII for SMJ320C31 (see Figure 17)

			'C31	-40	'LC3	1-40	'C31	I- 5 0	'C31	-60	
NO.			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
25	t _d (H3H-XF0L)	Delay time, H3 high to XF0 low		13		13		12		11	ns
26	t _{su(XF1-H1L)}	Setup time, XF1 before H1 low	9		10		8		8		ns
27	^t h(H1L-XF1)	Hold time, XF1 after H1 low	0		0		0		0		ns

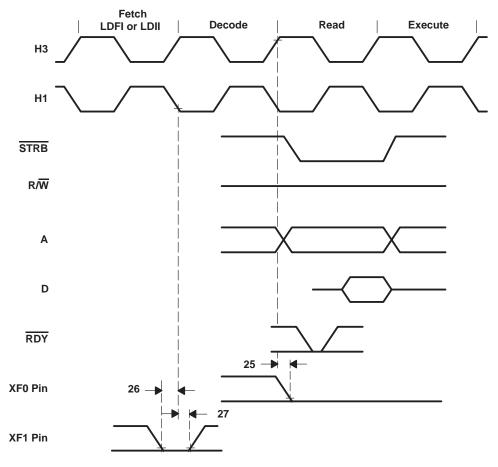


Figure 17. Timing for XF0 and XF1 When Executing LDFI or LDII

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

XF0 timing when executing STFI and STII[†]

The following table defines the timing parameters for the XF0 pin during execution of STFI or STII.

timing for XF0 when executing STFI or STII (see Figure 18)

NO.		'C31-40 'LC31-40	'C31-50	'C31-60	UNIT
		MIN MAX	MIN MAX	MIN MAX	
28	t _{d(H3H-XF0H)} Delay time, H3 high to XF0 high	13	12	11	ns

[†] XF0 is always set high at the beginning of the execute phase of the interlock-store instruction. When no pipeline conflicts occur, the address of the store is also driven at the beginning of the execute phase of the interlock-store instruction. However, if a pipeline conflict prevents the store from executing, the address of the store will not be driven until the store can execute.

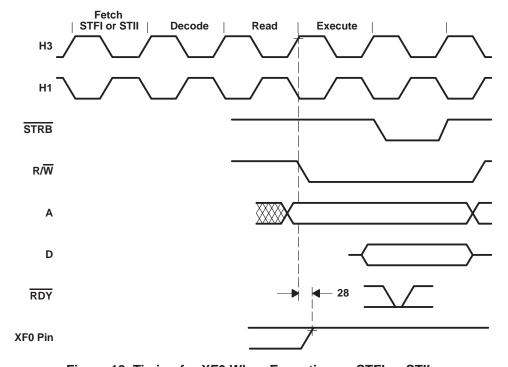


Figure 18. Timing for XF0 When Executing an STFI or STII

XF0 and XF1 timing when executing SIGI

The following table defines the timing parameters for the XF0 and XF1 pins during execution of SIGI.

timing for XF0 and XF1 when executing SIGI for SMJ320C31 (see Figure 19)

NO			'C31	-40	'LC3	1-40	'C31	-50	'C31	I-60	
NO.			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
29	t _d (H3H-XF0L)	Delay time, H3 high to XF0 low		13		13		12		11	ns
30	td(H3H-XF0H)	Delay time, H3 high to XF0 high		13		13		12		11	ns
31	t _{su(XF1-H1L)}	Setup time, XF1 before H1 low	9		10		8		8		ns
32	th(H1L-XF1)	Hold time, XF1 after H1 low	0		0		0	·	0	·	ns

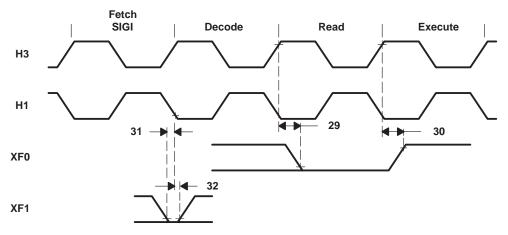


Figure 19. Timing for XF0 and XF1 When Executing SIGI

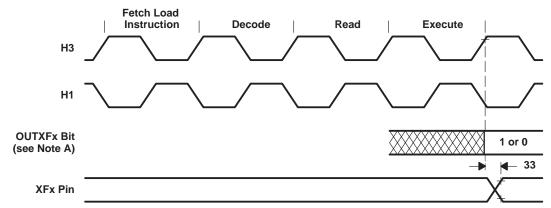
SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

loading when XF is configured as an output

The following table defines the timing parameter for loading the XF register when the XFx pin is configured as an output.

timing for loading the XF register when configured as an output pin (see Figure 20)

NO.		_	31-40 C31-40	,C3	1-50	,C3,	1-60	UNIT
		MI	N MAX	MIN	MAX	MIN	MAX	
33	t _{v(H3H-XF)} Valid time, H3 high to XFx		13		12		11	ns



NOTE A: OUTXFx represents either bit 2 or 6 of the IOF register.

Figure 20. Timing for Loading XF Register When Configured as an Output Pin



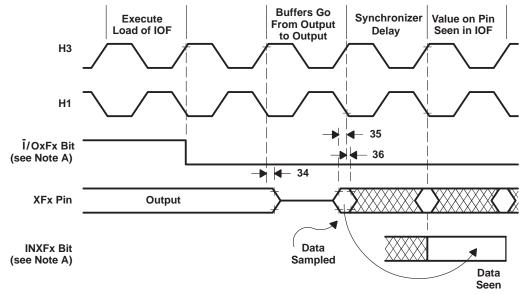
changing XFx from an output to an input

The following table defines the timing parameters for changing the XFx pin from an output pin to an input pin.

timing of XFx changing from output to input mode for SMJ320C31 (see Figure 21)

			'C31-	40	'LC3	1-40	'C31	-50	'C31	-60	LINUT
NO.			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
34	th(H3H-XF)	Hold time, XFx after H3 high		13*		13*		12*		11*	ns
35	t _{su(XF-H1L)}	Setup time, XFx before H1 low	9		10		8		8		ns
36	^t h(H1L-XF)	Hold time, XFx after H1 low	0		0		0		0		ns

^{*} This parameter is not production tested.



NOTE A: 1/OxFx represents either bit 1 or bit 5 of the IOF register, and INXFx represents either bit 3 or bit 7 of the IOF register.

Figure 21. Timing for Change of XFx From Output to Input Mode

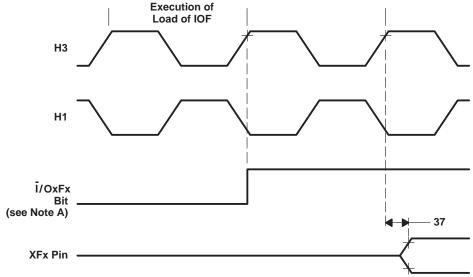
SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

changing XFx from an input to an output

The following table defines the timing parameter for changing the XFx pin from an input pin to an output pin.

timing for XFx changing from input to output mode (see Figure 22)

NO.			'C31 'LC3		,C3,	1-50	'C31	I-60	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
37	t _d (H3H-XFIO)	Delay time, H3 high to XFx switching from input to output		17		17		16	ns



NOTE A: 1/OxFx represents either bit 1 or bit 5 of the IOF register.

Figure 22. Timing for Change of XFx From Input to Output Mode

reset timing

RESET is an asynchronous input that can be asserted at any time during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 23 occurs; otherwise, an additional delay of one clock cycle is possible.

The asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.

Resetting the device initializes the primary- and expansion-bus control registers to seven software wait states and therefore results in slow external accesses until these registers are initialized.

HOLD is an asynchronous input and can be asserted during reset.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

RESET timing (see Figure 23)

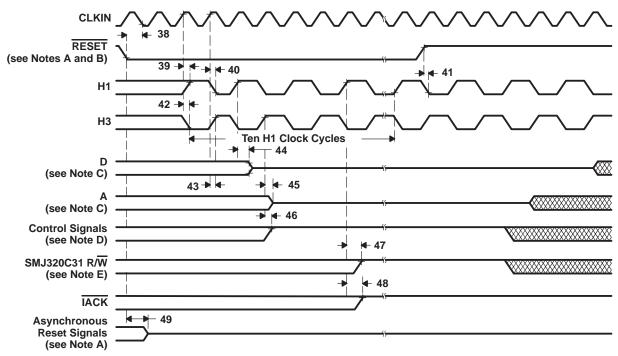
			'C31	-40	'LC3	1-40	'C31	-50	'C31	-60	
NO.			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
38	t _{su} (RESET-CIL)	Setup time, RESET before CLKIN low	10	P†*	10	P†*	10	P†*	7	P†*	ns
39	td(CLKINH-H1H)	Delay time, CLKIN high to H1 high (see Note 4)	2	14	2	14	2	10	2	10	ns
40	^t d(CLKINH-H1L)	Delay time, CLKIN high to H1 low (see Note 4)	2	14	2	14	2	10	2	10	ns
41	^t su(RESETH-H1L)	Setup time, RESET high before H1 low and after ten H1 clock cycles	9		9		7		6		ns
42	td(CLKINH-H3L)	Delay time, CLKIN high to H3 low (see Note 4)	2	14	2	14	2	10	2	10	ns
43	td(CLKINH-H3H)	Delay time, CLKIN high to H3 high (see Note 4)	2	14	2	14	2	10	2	10	ns
44	^t dis(H1H-DZ)	Disable time, H1 high to D (high impedance)		15*		13*		12*		11*	ns
45	^t dis(H3H-AZ)	Disable time, H3 high to A (high impedance)		9*		9*		8*		7*	ns
46	td(H3H-CONTROLH)	Delay time, H3 high to control signals high		9*		9*		8*		7*	ns
47	^t d(H1H-RWH)	Delay time, H1 high to R/\overline{W} high		9*		9*		8*		7*	ns
48	^t d(H1H-IACKH)	Delay time, H1 high to IACK high		9*		9*		8*		7*	ns
49	^t dis(RESETL-ASYNCH)	Disable time, RESET low to asynchronous reset signals disabled (high impedance)		21*		21*		17*		14*	ns

NOTE 4: See Figure 12 and Figure 13 for typical temperature dependence.

[†]P = t_{C(CI)}
* This parameter is not production tested.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

RESET timing (continued)



NOTES: A. Asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.

- B. RESET is an asynchronous input and can be asserted at any point during a clock cycle. If the specified timings are met, the exact sequence shown occurs; otherwise, an additional delay of one clock cycle is possible.
- C. In microprocessor mode, the reset vector is fetched twice, with seven software wait states each time. In microcomputer mode, the reset vector is fetched twice, with no software wait states.
- D. Control signals include STRB.
- E. The $R\overline{W}$ outputs are placed in a high-impedance state during reset and can be provided with a resistive pullup, nominally $18-22 \text{ k}\Omega$, if undesirable spurious writes are caused when these outputs go low.

Figure 23. Timing for RESET



SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

interrupt response timing

The following table defines the timing parameters for the $\overline{\text{INT}}$ signals.

timing for INT3-INT0 response (see Figure 24)

	١۵			'C31-	-40	'LC3	1-40	'C31	-50	'C31	-60	
N	10.			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
5	50	t _{su} (INT-H1L)	Setup time, INT3-INT0 before H1 low	13		15		11		8		ns
5	51	tw(INT)	Pulse duration, interrupt to ensure only one interrupt	Р	2P†*	Р	2P†*	Р	2P†*	Р	2P†*	ns

 $[\]overline{\uparrow}P = t_{C(H)}$

The interrupt (INT) pins are asynchronous inputs that can be asserted at any time during a clock cycle. The SMJ320C3x interrupts are level-sensitive, not edge-sensitive. Interrupts are detected on the falling edge of H1. Therefore, interrupts must be set up and held to the falling edge of H1 for proper detection. The CPU and DMA respond to detected interrupts on instruction-fetch boundaries only.

For the processor to recognize only one interrupt on a given input, an interrupt pulse must be set up and held to:

- A minimum of one H1 falling edge
- No more than two H1 falling edges

The SMJ320C3x can accept an interrupt from the same source every two H1 clock cycles.

If the specified timings are met, the exact sequence shown in Figure 24 occurs; otherwise, an additional delay of one clock cycle is possible.



^{*} This parameter is not production tested.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

timing parameters for INT3-INT0 response (continued)

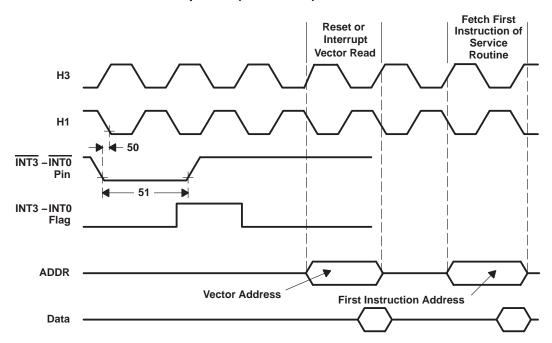


Figure 24. Timing for INT3-INT0 Response



interrupt-acknowledge timing

The IACK output goes active on the first half-cycle (HI rising) of the decode phase of the IACK instruction and goes inactive at the first half-cycle (HI rising) of the read phase of the IACK instruction.

timing for IACK (see Note 5 and Figure 25)

NO.			'C3	1-40 31-40	'C3	1-50	'C31	1-60	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
52	td(H1H-IACKL)	Delay time, H1 high to IACK low		9		7		6	ns
53	td(H1H-IACKH)	Delay time, H1 high to IACK high		9		7		6	ns

NOTE 5: IACK goes active on the first half-cycle (H1 rising) of the decode phase of the IACK instruction and goes inactive at the first half-cycle (H1 rising) of the read phase of the IACK instruction. Because of pipeline conflicts, IACK remains low for one cycle even if the decode phase of the IACK instruction is extended.

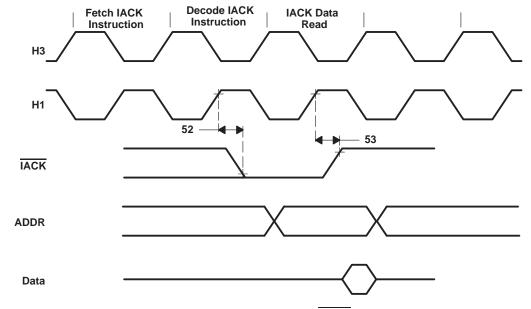


Figure 25. Timing for IACK

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

serial-port timing for SMJ320C31-40 and SMJ320LC31-40 (see Figure 26 and Figure 27)

NO.					1-40 1-40	UNIT
				MIN	MAX	
54	td(H1H-SCK)	Delay time, H1 high to internal CLKX/R			13	ns
55		Cycle time, CLKX/R	CLKX/R ext	t _{C(H)} x2.6		20
55	t _c (SCK)	Cycle time, CLKX/R	CLKX/R int	t _{c(H)} x2	t _{c(H)} x2 ³²	ns
56		Pulse duration CLIVV/D high/low	CLKX/R ext	t _{C(H)} +10		20
50	tw(SCK)	Pulse duration, CLKX/R high/low	CLKX/R int	[t _{c(SCK)} /2]-5	[t _{C(SCK)} /2]+5	ns
57	tr(SCK)	Rise time, CLKX/R			7	ns
58	tf(SCK)	Fall time, CLKX/R			7	ns
		Palacetiana OHW to PV collist	CLKX ext		30	
59	td(C-DX)	Delay time, CLKX to DX valid	CLKX int		17	ns
-00		Oates the DD before OHKD less	CLKR ext	9		
60	^t su(DR-CLKRL)	Setup time, DR before CLKR low	CLKR int	21		ns
C4		Hold fire a DD from CLVD low	CLKR ext	9		
61	^t h(CLKRL-DR)	Hold time, DR from CLKR low	CLKR int	0		ns
-00		Deleviting CLIVY to internal ECV high flow	CLKX ext		27	
62	^t d(C-FSX)	Delay time, CLKX to internal FSX high/low	CLKX int		15	ns
-00		Cation time. ECD hafara CLIVD law	CLKR ext	9		
63	^t su(FSR-CLKRL)	Setup time, FSR before CLKR low	CLKR int	9		ns
		Hald the FOV/D have to a CHV/D have	CLKX/R ext	9		
64	th(SCKL-FS)	Hold time, FSX/R input from CLKX/R low	CLKX/R int	0		ns
C.F.		Cation times automad ECV before CLIVY	CLKX ext	-[t _{C(H)} -8]*	[t _C (SCK)/2]-10*	
65	^t su(FSX-C)	Setup time, external FSX before CLKX	CLKX int	[t _{C(H)} -21]*	t _c (SCK)/2*	ns
-00		Delay time, CLKX to first DX bit, FSX	CLKX ext		30*	
66	td(CH-DX)V	precedes CLKX high	CLKX int		18*	ns
67	td(FSX-DX)V	Delay time, FSX to first DX bit, CLKX precede	es FSX		30*	ns
68	^t d(CH-DXZ)	Delay time, CLKX high to DX high impedance bit	e following last data		17*	ns

^{*} This parameter is not production tested.



SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

serial-port timing for SMJ320C31-50 (see Figure 26 and Figure 27)

				,C3	1-50	
NO.				MIN	MAX	UNIT
54	td(H1H-SCK)	Delay time, H1 high to internal CLKX/R			10	ns
		Oracle Core OLIVID	CLKX/R ext	t _{C(H)} x2.6		
55	t _c (SCK)	Cycle time, CLKX/R	CLKX/R int	t _{c(H)} x2	t _{C(H)} x2 ³²	ns
50		Dulas duration OLIVV/D high/law	CLKX/R ext	t _{c(H)} +10		
56	tw(SCK)	Pulse duration, CLKX/R high/low	CLKX/R int	[t _{c(SCK)} /2]-5	[t _{c(SCK)} /2]+5	ns
57	t _{r(SCK)}	Rise time, CLKX/R			6	ns
58	t _f (SCK)	Fall time, CLKX/R			6	ns
		B. L. di COLIVIA BY THE	CLKX ext		24	
59	^t d(C-DX)	Delay time, CLKX to DX valid	CLKX int		16	ns
			CLKR ext	9		
60	tsu(DR-CLKRL)	Setup time, DR before CLKR low	CLKR int	17		ns
			CLKR ext	7		
61	^t h(CLKRL-DR)	Hold time, DR from CLKR low	CLKR int	0		ns
		D 1 OLIV	CLKX ext		22	
62	^t d(C-FSX)	Delay time, CLKX to internal FSX high/low	CLKX int		15	ns
		0	CLKR ext	7		
63	tsu(FSR-CLKRL)	Setup time, FSR before CLKR low	CLKR int	7		ns
0.4		11.11.1: E0V/D: ./	CLKX/R ext	7		
64	th(SCKL-FS)	Hold time, FSX/R input from CLKX/R low	CLKX/R int	0		ns
		0	CLKX ext	-[t _{C(H)} -8]*	[t _{C(SCK)} /2]-10*	
65	t _{su(FSX-C)}	Setup time, external FSX before CLKX	CLKX int	-[t _{C(H)} -21]*	tc(SCK)/2*	ns
00		Delay time, CLKX to first DX bit, FSX	CLKX ext		24*	
66	^t d(CH-DX)V	precedes CLKX high	CLKX int		14*	ns
67	td(FSX-DX)V	Delay time, FSX to first DX bit, CLKX precede	es FSX		24*	ns
68	^t d(CH-DXZ)	Delay time, CLKX high to DX high impedance data bit	e following last		14*	ns

^{*} This parameter is not production tested.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

serial-port timing for SMJ320C31-60 (see Figure 26 and Figure 27)

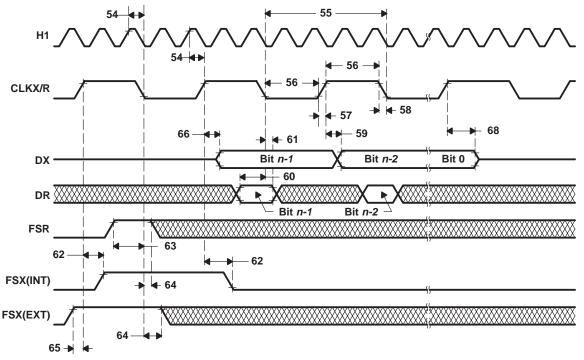
				,C3	1-60	
NO.				MIN	MAX	UNIT
54	td(H1H-SCK)	Delay time, H1 high to internal CLKX/R			8	ns
		0.1.4.0010075	CLKX/R ext	t _{C(H)} x2.6		
55	t _C (SCK)	Cycle time, CLKX/R	CLKX/R int	t _{c(H)} x2	t _{c(H)} x2 ³²	ns
		5	CLKX/R ext	t _{c(H)} +10		
56	tw(SCK)	Pulse duration, CLKX/R high/low	CLKX/R int	[t _C (SCK)/2]-5	[t _{C(SCK)} /2]+5	ns
57	t _{r(SCK)}	Rise time, CLKX/R			5	ns
58	t _f (SCK)	Fall time, CLKX/R			5	ns
			CLKX ext		20	
59	^t d(C-DX)	Delay time, CLKX to DX valid	CLKX int		15	ns
			CLKR ext	8		
60	tsu(DR-CLKRL)	Setup time, DR before CLKR low	CLKR int	15		ns
			CLKR ext	6		
61	^t h(CLKRL-DR)	Hold time, DR from CLKR low	CLKR int	0		ns
		5	CLKX ext		20	
62	^t d(C-FSX)	Delay time, CLKX to internal FSX high/low	CLKX int		14	ns
		0	CLKR ext	6		
63	tsu(FSR-CLKRL)	Setup time, FSR before CLKR low	CLKR int	6		ns
0.4		Hald the FOVID have force OLIVVID have	CLKX/R ext	6		
64	th(SCKL-FS)	Hold time, FSX/R input from CLKX/R low	CLKX/R int	0		ns
0.5		0	CLKX ext	-[t _{C(H)} -8]*	[t _C (SCK)/2]-10*	
65	tsu(FSX-C)	Setup time, external FSX before CLKX	CLKX int	-[t _{C(H)} -21]*	t _{c(SCK)} /2*	ns
00		Delay time, CLKX to first DX bit, FSX	CLKX ext		20*	
66	^t d(CH-DX)V	precedes CLKX high	CLKX int		12*	ns
67	td(FSX-DX)V	Delay time, FSX to first DX bit, CLKX precede	es FSX		20*	ns
68	[†] d(CH-DXZ)	Delay time, CLKX high to DX high impedance data bit	following last		12*	ns

^{*} This parameter is not production tested.



data-rate timing modes

Unless otherwise indicated, the data-rate timings shown in Figure 26 and Figure 27 are valid for all serial-port modes, including handshake. For a functional description of serial-port operation, see subsection 8.2.12 of the *TMS320C3x User's Guide* (literature number SPRU031).



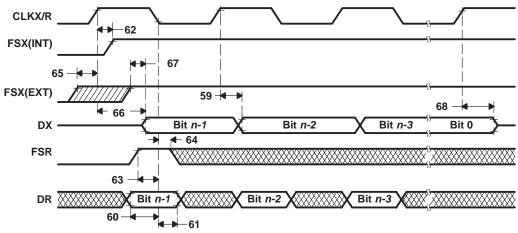
NOTES: A. Timing diagrams show operations with CLKXP = CLKRP = FSXP = FSRP = 0.

B. Timing diagrams depend on the length of the serial-port word, where n = 8, 16, 24, or 32 bits, respectively.

Figure 26. Timing for Fixed Data-Rate Mode

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

data-rate timing modes (continued)



NOTES: A. Timing diagrams show operation with CLKXP = CLKRP = FSXP = FSRP = 0.

- B. Timing diagrams depend on the length of the serial-port word, where n = 8, 16, 24, or 32 bits, respectively.
- C. The timings that are not specified expressly for the variable data-rate mode are the same as those that are specified for the fixed data-rate mode.

Figure 27. Timing for Variable Data-Rate Mode



SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

HOLD timing

HOLD is an asynchronous input that can be asserted at any time during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 27 occurs; otherwise, an additional delay of one clock cycle is possible.

The NOHOLD bit of the primary-bus control register overrides the HOLD signal. When this bit is set, the device comes out of hold and prevents future hold cycles.

Asserting HOLD prevents the processor from accessing the primary bus. Program execution continues until a read from or a write to the primary bus is requested. In certain circumstances, the first write is pending, thus allowing the processor to continue until a second write is encountered.

timing for HOLD/HOLDA (see Figure 28)

				40	'LC31	-40	'C31-	50	'C31-	LINUT	
NO.			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
69	tsu(HOLD-H1L)	Setup time, HOLD before H1 low	13		13		10		8		ns
70	t _V (H1L-HOLDA)	Valid time, HOLDA after H1 low	0†	9	0*	9	0*	7	0*	6	ns
71	tw(HOLD) [†]	Pulse duration, HOLD low	2t _{c(H)}		2t _{c(H)}		2t _{c(H)}		2t _{c(H)}		ns
72	^t w(HOLDA)	Pulse duration, HOLDA low	t _{cH} -5*		ns						
73	td(H1L-SH)H	Delay time, H1 low to STRB high for a HOLD	0*	9	0*	9	0*	7	0*	6	ns
74	^t dis(H1L-S)	Disable time, H1 low to STRB to the high-impedance state	0*	9*	0*	9*	0*	7*	0*	7*	ns
75	ten(H1L-S)	Enable time, H1 low to STRB enabled (active)	0*	9	0*	9	0*	7	0*	6	ns
76	^t dis(H1L-RW)	Disable time, H1 low to R/W to the high-impedance state	0*	9*	0*	9*	0*	8*	0*	7*	ns
77	ten(H1L-RW)	Enable time, H1 low to R/W enabled (active)	0*	9	0*	9	0*	7	0*	6	ns
78	^t dis(H1L-A)	Disable time, H1 low to address to the high-impedance state	0*	9*	0*	10*	0*	8*	0*	7*	ns
79	ten(H1L-A)	Enable time, H1 low to address enabled (valid)	0*	13	0*	13	0*	10	0*	11?	ns
80	^t dis(H1H-D)	Disable time, H1 high to data to the high-impedance state	0*	12*	0*	9*	0*	10*	0*	7*	ns

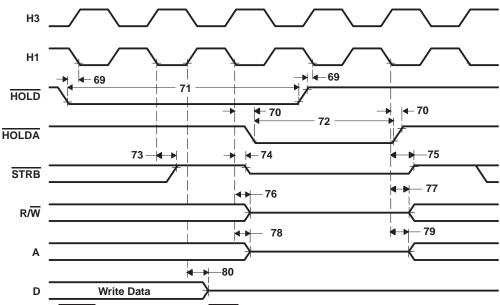
[†] HOLD is an asynchronous input and can be asserted at any point during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 28 occurs; otherwise, an additional delay of one clock cycle is possible.



^{*} This parameter is not production tested.

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

HOLD timing (continued)



NOTE A: HOLDA goes low in response to HOLD going low and continues to remain low until one H1 cycle after HOLD goes back high.

Figure 28. Timing for HOLD/HOLDA



general-purpose I/O timing

Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The contents of the internal control registers associated with each peripheral define the modes for these pins.

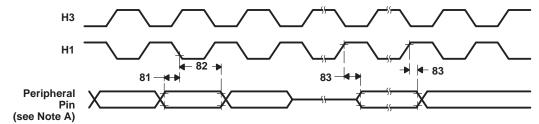
peripheral pin I/O timing

The table, timing parameters for peripheral pin general-purpose I/O, defines peripheral pin general-purpose I/O timing parameters.

timing requirements for peripheral pin general-purpose I/O (see Note 6 and Figure 29)

NO.			'C31-33		'C31-40 'LC31-40		'C31-50		'C31-60		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
81	tsu(GPIO-H1L)	Setup time, general-purpose input before H1 low	12		10		9		8		ns
82	t _h (H1L-GPIO)	Hold time, general-purpose input after H1 low	0		0		0		0		ns
83	td(H1H-GPIO)	Delay time, general-purpose output after H1 high		15		13		10		8	ns

NOTE 6: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.



NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

Figure 29. Timing for Peripheral Pin General-Purpose I/O

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

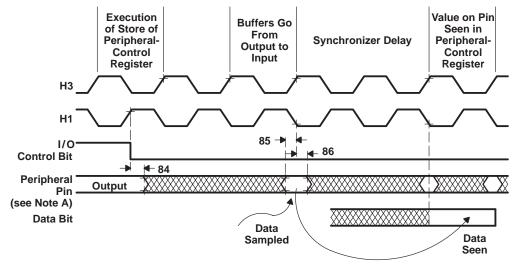
changing the peripheral pin I/O modes

The following tables show the timing parameters for changing the peripheral pin from a general-purpose output pin to a general-purpose input pin and vice versa.

timing requirements for peripheral pin changing from general-purpose output to input mode (see Note 6 and Figure 30)

NO.		'C31 'LC3	-	'C3	1-50	'C31-60		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	
84	th(H1H)	Hold time, peripheral pin after H1 high		13		10		8	ns
85	tsu(GPIO-H1L)	Setup time, peripheral pin before H1 low	9		9		8		ns
86	th(H1L-GPIO)	Hold time, peripheral pin after H1 low	0	·	0	·	0		ns

NOTE 6: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.



NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

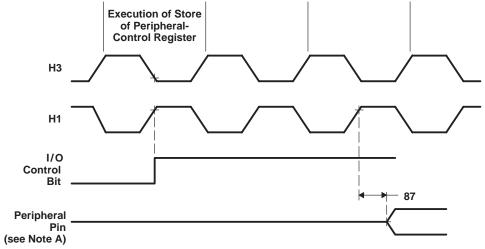
Figure 30. Timing for Change of Peripheral Pin From General-Purpose Output to Input Mode

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

timing for peripheral pin changing from general-purpose input to output mode (see Note 6 and Figure 31)

NO.			'C31 'LC3	-	'C31	I- 5 0	'C31	-60	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
87	td(H1H-GPIO)	Delay time, H1 high to peripheral pin switching from input to output		13		10		8	ns

NOTE 6: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.



NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

Figure 31. Timing for Change of Peripheral Pin From General-Purpose Input to Output Mode

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

timer pin timing

Valid logic-level periods and polarity are specified by the contents of the internal control registers.

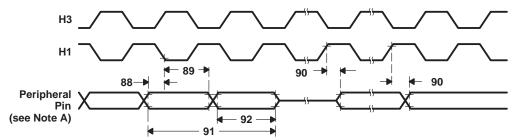
The following tables define the timing requirements for the timer pin.

timing for timer pin (see Figure 32 and Note 7)

NO.				'C31- 'LC3' 'C31-	1-40	'C31-	-60	UNIT
				MIN	MAX	MIN	MAX	
88	tsu(TCLK-H1L)	Setup time, TCLK extended before H1 low	ernal	10		6		ns
89	th(H1L-TCLK)	Hold time, TCLK exter H1 low	nal after	0		0		ns
90	^t d(H1H-TCLK)	Delay time, H1 high to internal valid	TCLK		9		8	ns
04		Cycle time TCLK	TCLK ext	t _{C(H)} ×2.6		t _{C(H)} ×2.6		20
91	t _C (TCLK)	Cycle time, TCLK	TCLK int	t _{c(H)} ×2	t _{c(H)} ×2 ^{32*}	t _{c(H)} ×2	t _{c(H)} ×2 ^{32*}	ns
92	t (TOLIO	Pulse duration, TCLK e		t _{c(H)} +10		t _{c(H)} +10		ns
92 t _{w(TCLK)}	TCLK high/low	TCLK int	[t _C (TCLK)/2]-5	[t _C (TCLK)/2]+5	[t _C (TCLK)/2]-5	[t _{C(TCLK)} /2]+5	115	

NOTE 7: Numbers 88 and 89 are applicable for a synchronous input clock. Timing parameters 91 and 92 are applicable for an asynchronous input clock.

^{*} This parameter is not production tested.



NOTE A: HOLDA goes low in response to HOLD going low and continues to remain low until one H1 cycle after HOLD goes back high.

Figure 32. Timing for Timer Pin

SHZ pin timing

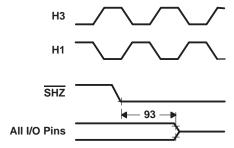
The following table defines the timing parameter for the SHZ pin.

timing parameters for SHZ (see Figure 33)

NO.		'C3 'LC:		UNIT
		MIN	MAX	
93	t _{dis(SHZ)} Disable time, SHZ low to all O, I/O pins disabled (high impedance)	0*	2P†*	ns

 $[\]dagger P = t_{C(CI)}$

^{*} This parameter is not production tested.



NOTE A: Enabling SHZ destroys SMJ320C3x register and memory contents.

Assert SHZ = 1 and reset the SMJ320C3x to restore it to a known condition.

Figure 33. Timing for SHZ

Not Recommended for New Designs

SMJ320C31, SMJ320LC31, SMQ320LC31 DIGITAL SIGNAL PROCESSORS

SGUS026G - APRIL 1998 - REVISED SEPTEMBER 2006

part order information

DEVICE	TECHNOLOGY	POWER SUPPLY	OPERATING FREQUENCY	PACKAGE TYPE	PROCESSING LEVEL
5962-9205803MXA	0.6-μm CMOS	5 V ± 5%	40 MHz	Ceramic 141-pin staggered PGA	DSCC SMD
SMJ320C31GFAM40	0.6-μm CMOS	5 V ± 5%	40 MHz	Ceramic 141-pin staggered PGA	QML
SM320C31GFAM40	0.6-μm CMOS	5 V ± 5%	40 MHz	Ceramic 141-pin staggered PGA	Std
5962-9205803MYA	0.6-μm CMOS	5 V ± 5%	40 MHz	Ceramic 132-pin quad flatpack with nonconductive tie bar.	DSCC SMD
SMJ320C31HFGM40	0.6-μm CMOS	5 V ± 5%	40 MHz	Ceramic 132-lead quad flatpack with a nonconductive tie bar	QML
SM320C31HFGM40	0.6-μm CMOS	5 V ± 5%	40 MHz	Ceramic 132-lead quad flatpack with a nonconductive tie bar	Std
5962-9205803Q9A	0.72-μm CMOS	5 V ± 5%	40 MHz	C31-40 KGD (known good die)	DSCC SMD
SMJ320C31KGDM40B	0.72-μm CMOS	5 V ± 5%	40 MHz	C31-40 KGD (known good die)	QML
5962-9205804MXA	0.6-μm CMOS	5 V ± 5%	50 MHz	Ceramic 141-pin staggered PGA	DSCC SMD
SMJ320C31GFAM50	0.6-μm CMOS	5 V ± 5%	50 MHz	Ceramic 141-pin staggered PGA	QML
SM320C31GFAM50	0.6-μm CMOS	5 V ± 5%	50 MHz	Ceramic 141-pin staggered PGA	Std
5962-9205804MYA	0.6-μm CMOS	5 V ± 5%	50 MHz	Ceramic 132-pin quad flatpack with nonconductive tie bar.	DSCC SMD
SMJ320C31HFGM50	0.6-μm CMOS	5 V ± 5%	50 MHz	Ceramic 132-lead quad flatpack with nonconductive tie bar	QML
SM320C31HFGM50	0.6-μm CMOS	5 V ± 5%	50 MHz	Ceramic 132-lead quad flatpack with nonconductive tie bar	Std
5962-9205805QXA	0.6-μm CMOS	5 V ± 5%	60 MHz	Ceramic 141-pin staggered PGA	DSCC SMD
SMJ320C31GFAS60	0.6-μm CMOS	5 V ± 5%	60 MHz	Ceramic 141-pin staggered PGA	QML
SM320C31GFAS60	0.6-μm CMOS	5 V ± 5%	60 MHz	Ceramic 141-pin staggered PGA	Std
5962-9205805QYA	0.6-μm CMOS	5 V ± 5%	60 MHz	Ceramic 132-pin quad flatpack with nonconductive tie bar.	DSCC SMD
SMJ320C31HFGS60	0.6-μm CMOS	5 V ± 5%	60 MHz	Ceramic 132-lead quad flatpack with nonconductive tie bar	QML
SM320C31HFGS60	0.6-μm CMOS	5 V ± 5%	60 MHz	Ceramic 132-lead quad flatpack with nonconductive tie bar	Std
5962-9760601NXB	0.72-μm CMOS	3.3 V ± 5%	40 MHz	Plastic 132-lead good flatpack	DSCC SMD
SMQ320LC31PQM40	0.72-μm CMOS	3.3 V ± 5%	40 MHz	Plastic 132-lead good flatpack	QML
5962-9760601Q9A	0.72-μm CMOS	3.3 V ± 5%	40 MHz	LC31-40 KGD (known good die)	DSCC SMD
SMJ320LC31KGDM40B	0.72-μm CMOS	3.3 V ± 5%	40 MHz	LC31-40 KGD (known good die)	QML



part order information (continued) SMJ 320 (L) C **GFA** 50 31 M **SPEED RANGE** PREFIX -40 = 40 MHzSMJ = MIL-PRF-38535 (QML)50 = 50 MHzSM = Standard Processing 60 = 60 MHzSMQ = Plastic (QML) **TEMPERATURE RANGE** $M = -55^{\circ}C \text{ to } 125^{\circ}C$ $S = -55^{\circ}C \text{ to } 105^{\circ}C$ $L = 0^{\circ}C \text{ to } 70^{\circ}C$ **DEVICE FAMILY** 320 = SMJ320 Family **TECHNOLOGY PACKAGE TYPE** L = Low Voltage GFA = 141-Pin Ceramic Staggered Pin Grid (3.3-V option) Array Ceramic Package HFG = 132-Pin Ceramic Quad Flatpack with a nonconductive tie bar **TECHNOLOGY** PQ 132-lead Plastic Quad Flatpack C = CMOSTΑ 132-lead TAB frame with polyimide encapsulant DEVICE -TB 132-lead TAB frame, bare-die option 31 = '320C31 or '320LC31 KGD = Known Good Die

Figure 34. Device Nomenclature





17-Mar-2017

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9205803MXA	NRND	CPGA	GFA	141	1	TBD	Call TI	Call TI	-55 to 125	5962-9205803MX A SMJ320C31GFAM4 0	
5962-9205803MYA	NRND	CFP	HFG	132	1	TBD	Call TI	Call TI	-55 to 125	5962-9205803MY A SMJ320C31HFGM4 0	
5962-9205804MXA	NRND	CPGA	GFA	141	1	TBD	Call TI	Call TI	-55 to 125	5962-9205804MX A SMJ320C31GFAM5 0	
5962-9205804MYA	NRND	CFP	HFG	132	1	TBD	Call TI	Call TI	-55 to 125	5962-9205804MY A SMJ320C31HFGM5 0	
5962-9205805QXA	NRND	CPGA	GFA	141	1	TBD	Call TI	Call TI	-55 to 95	5962-9205805QX A SMJ320C31GFAS6 0	
5962-9205805QYA	NRND	CFP	HFG	132	1	TBD	Call TI	Call TI	-55 to 95	5962-9205805QY A SMJ320C31HFGS6 0	
5962-9760601NXB	NRND	BQFP	PQ	132	1	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR	-55 to 125	5962-9760601NX B SMQ320LC31PQM4 0	
SM320C31GFAM50	NRND	CPGA	GFA	141	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	SM320C31GFAM50	
SM320C31HFGM40	NRND	CFP	HFG	132	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	SM320C31HFGM40	
SM320C31HFGM50	NRND	CFP	HFG	132	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	SM320C31HFGM50	
SMJ320C31GFAM40	NRND	CPGA	GFA	141	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	5962-9205803MX A SMJ320C31GFAM4 0	
SMJ320C31GFAM50	NRND	CPGA	GFA	141	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	5962-9205804MX	





17-Mar-2017

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
										A SMJ320C31GFAM5 0	
SMJ320C31GFAS60	NRND	CPGA	GFA	141	1	TBD	Call TI	N / A for Pkg Type	-55 to 95	5962-9205805QX A SMJ320C31GFAS6 0	
SMJ320C31HFGM40	NRND	CFP	HFG	132	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	5962-9205803MY A SMJ320C31HFGM4 0	
SMJ320C31HFGM50	NRND	CFP	HFG	132	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	5962-9205804MY A SMJ320C31HFGM5 0	
SMJ320C31HFGS60	NRND	CFP	HFG	132	1	TBD	Call TI	N / A for Pkg Type	-55 to 95	5962-9205805QY A SMJ320C31HFGS6 0	
SMQ320LC31PQM40	NRND	BQFP	PQ	132	1	TBD	Call TI	Call TI	-55 to 125		

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.





17-Mar-2017

- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SM320C31, SMJ320C31:

Catalog: TMS320C31, TMS320C31

Military: SMJ320C31

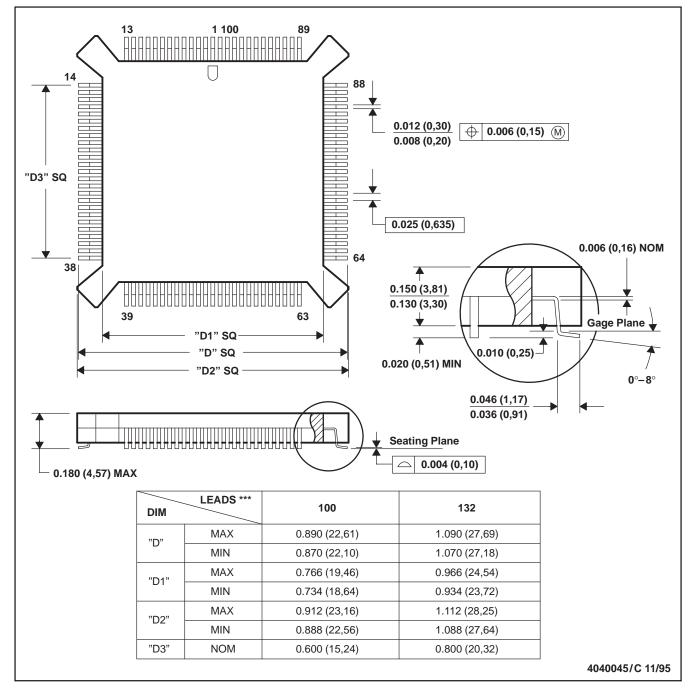
NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PQ (S-PQFP-G***)

100 LEAD SHOWN

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in inches (millimeters).

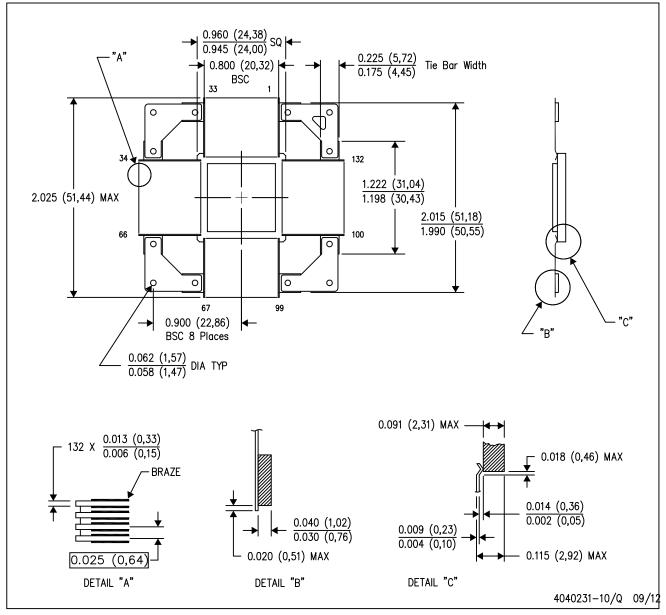
B. This drawing is subject to change without notice.

C. Falls within JEDEC MO-069



HFG (S-CQFP-F132)

CERAMIC QUAD FLATPACK WITH NCTB



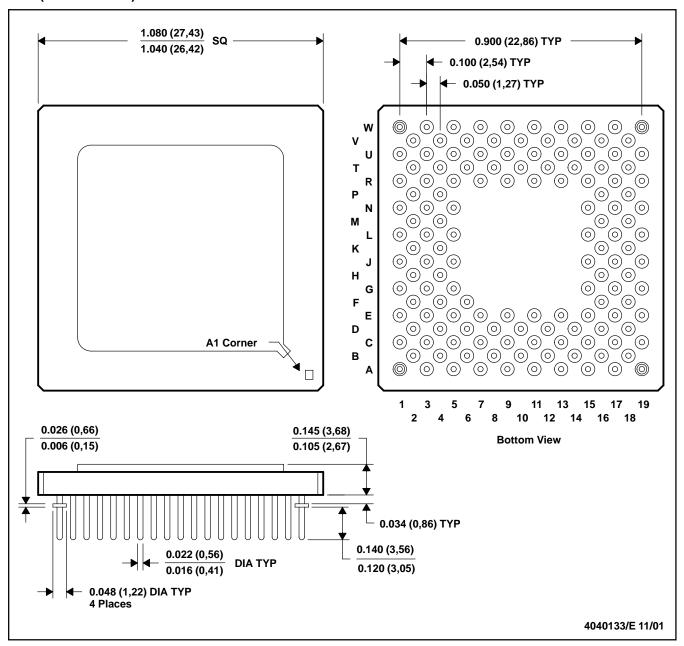
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Ceramic quad flatpack with flat leads brazed to non-conductive tie bar carrier.
- D. This package is hermetically sealed with a metal lid.
- E. The leads are gold plated and can be solderdipped.
- F. Leads not shown for clarity purposes.



GFA (S-CPGA-P141)

CERAMIC PIN GRID ARRAY



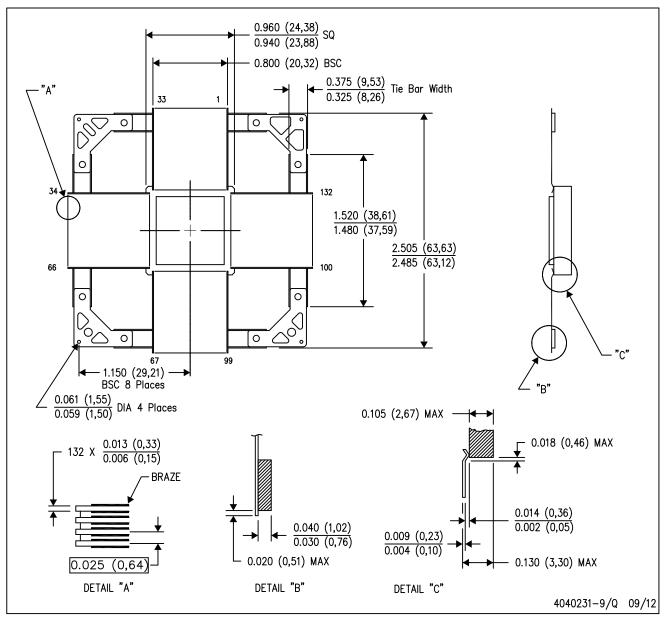
NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Index mark can appear on top or bottom, depending on package vendor.
- D. Pins are located within 0.010 (0,25) diameter of true position relative to each other at maximum material condition and within 0.030 (0,76) diameter relative to the edge of the ceramic.
- E. This package can be hermetically sealed with metal lids or with ceramic lids using glass frit.
- F. The pins can be gold-plated or solder-dipped.
- G. Falls within JEDEC MO-128AB



HFG (S-CQFP-F132)

CERAMIC QUAD FLATPACK WITH NCTB



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Ceramic quad flatpack with flat leads brazed to non-conductive tie bar carrier.
- D. This package is hermetically sealed with a metal lid.
- E. The leads are gold plated and can be solderdipped.
- F. Leads not shown for clarity purposes.
- G. Falls within JEDEC MO-113AC



IMPORTANT NOTICE

Texas Instruments Incorporated (TI) reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete.

TI's published terms of sale for semiconductor products (http://www.ti.com/sc/docs/stdterms.htm) apply to the sale of packaged integrated circuit products that TI has qualified and released to market. Additional terms may apply to the use or sale of other types of TI products and services.

Reproduction of significant portions of TI information in TI data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such reproduced documentation. Information of third parties may be subject to additional restrictions. Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyers and others who are developing systems that incorporate TI products (collectively, "Designers") understand and agree that Designers remain responsible for using their independent analysis, evaluation and judgment in designing their applications and that Designers have full and exclusive responsibility to assure the safety of Designers' applications and compliance of their applications (and of all TI products used in or for Designers' applications) with all applicable regulations, laws and other applicable requirements. Designer represents that, with respect to their applications, Designer has all the necessary expertise to create and implement safeguards that (1) anticipate dangerous consequences of failures, (2) monitor failures and their consequences, and (3) lessen the likelihood of failures that might cause harm and take appropriate actions. Designer agrees that prior to using or distributing any applications that include TI products, Designer will thoroughly test such applications and the functionality of such TI products as used in such applications.

TI's provision of technical, application or other design advice, quality characterization, reliability data or other services or information, including, but not limited to, reference designs and materials relating to evaluation modules, (collectively, "TI Resources") are intended to assist designers who are developing applications that incorporate TI products; by downloading, accessing or using TI Resources in any way, Designer (individually or, if Designer is acting on behalf of a company, Designer's company) agrees to use any particular TI Resource solely for this purpose and subject to the terms of this Notice.

TI's provision of TI Resources does not expand or otherwise alter TI's applicable published warranties or warranty disclaimers for TI products, and no additional obligations or liabilities arise from TI providing such TI Resources. TI reserves the right to make corrections, enhancements, improvements and other changes to its TI Resources. TI has not conducted any testing other than that specifically described in the published documentation for a particular TI Resource.

Designer is authorized to use, copy and modify any individual TI Resource only in connection with the development of applications that include the TI product(s) identified in such TI Resource. NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT OF TI OR ANY THIRD PARTY IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information regarding or referencing third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of TI Resources may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI RESOURCES ARE PROVIDED "AS IS" AND WITH ALL FAULTS. TI DISCLAIMS ALL OTHER WARRANTIES OR REPRESENTATIONS, EXPRESS OR IMPLIED, REGARDING RESOURCES OR USE THEREOF, INCLUDING BUT NOT LIMITED TO ACCURACY OR COMPLETENESS, TITLE, ANY EPIDEMIC FAILURE WARRANTY AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY DESIGNER AGAINST ANY CLAIM, INCLUDING BUT NOT LIMITED TO ANY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON ANY COMBINATION OF PRODUCTS EVEN IF DESCRIBED IN TI RESOURCES OR OTHERWISE. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, DIRECT, SPECIAL, COLLATERAL, INDIRECT, PUNITIVE, INCIDENTAL, CONSEQUENTIAL OR EXEMPLARY DAMAGES IN CONNECTION WITH OR ARISING OUT OF TI RESOURCES OR USE THEREOF, AND REGARDLESS OF WHETHER TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES.

Unless TI has explicitly designated an individual product as meeting the requirements of a particular industry standard (e.g., ISO/TS 16949 and ISO 26262), TI is not responsible for any failure to meet such industry standard requirements.

Where TI specifically promotes products as facilitating functional safety or as compliant with industry functional safety standards, such products are intended to help enable customers to design and create their own applications that meet applicable functional safety standards and requirements. Using products in an application does not by itself establish any safety features in the application. Designers must ensure compliance with safety-related requirements and standards applicable to their applications. Designer may not use any TI products in life-critical medical equipment unless authorized officers of the parties have executed a special contract specifically governing such use. Life-critical medical equipment is medical equipment where failure of such equipment would cause serious bodily injury or death (e.g., life support, pacemakers, defibrillators, heart pumps, neurostimulators, and implantables). Such equipment includes, without limitation, all medical devices identified by the U.S. Food and Drug Administration as Class III devices and equivalent classifications outside the U.S.

TI may expressly designate certain products as completing a particular qualification (e.g., Q100, Military Grade, or Enhanced Product). Designers agree that it has the necessary expertise to select the product with the appropriate qualification designation for their applications and that proper product selection is at Designers' own risk. Designers are solely responsible for compliance with all legal and regulatory requirements in connection with such selection.

Designer will fully indemnify TI and its representatives against any damages, costs, losses, and/or liabilities arising out of Designer's non-compliance with the terms and provisions of this Notice.